

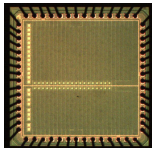
## Aging in Digital Circuits

### Characterization



Novel chip design for advanced characterization of digital gates

ASIC  
ATIUM

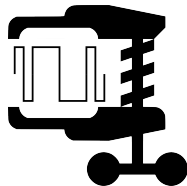


### Mitigation



New compression techniques to accurately scale defect-centric models from transistors to large digital circuits

Compression



### Exploitation



Understanding aging to obtain reliable hardware fingerprints through SRAM PUFs

Hardware  
security

